

	Type	L #	Hits	Search Text	Dbs	Time Stamp	Comments	Error Definition	Err ors
1	BRS	L1	1703	250/370.01,370.08,370.09,370.11,363.62,363.01.ccls. 1 and(inspec\$4 or devec\$4) same (integrate\$1 near3 circuit\$1 or wafer\$1 or "IC"chip\$1 or printed near3 circuits)	USPAT	2004/01/28 12:02			0
2	BRS	L2	300	2 and(collimator or collima\$4) same(x-ray or x-rays or x-raying or x-rayed or x-ray\$3 near3 beam\$1 or gamma near3 ray\$1)	USPAT	2004/01/28 12:04			0
3	BRS	L3	50	3 and (multiaperture or multi-aperture or multi adj1 aperture or plurality near3 apertures or grid\$2 or mesh\$2)	USPAT	2004/01/28 12:48			0
4	BRS	L4	15	((collimator or collima\$4) with(x-ray or x-rays or x-raying or x-rayed or x-ray\$3 near3 beam\$1 or gamma near3 ray\$1) same semiconductor near3 wafer)	USPAT	2004/01/28 12:51			0
5	BRS	L5	22	5 same (multiaperture or multi-aperture or multi adj1 aperture or plurality near3 apertures or grid\$2 or mesh\$2)	USPAT	2004/01/28 12:51			0
6	BRS	L6	0	5 and (multiaperture or multi-aperture or multi adj1 aperture or plurality near3 apertures or grid\$2 or mesh\$2)	USPAT	2004/01/28 12:52			0
7	BRS	L7	2	5 and (multiaperture or multi-aperture or multi adj1 aperture or plurality near3 apertures or grid\$2 or mesh\$2)	USPAT	2004/01/28 12:52			0

	Type	L #	Hits	Search Text	Dbs	Time Stamp	Comments	Error Definition	Err ors
1	BRS	L1	1703	250/370.01,370.08,370.09,370.11,363.62,363.01.ccls.	USPAT	2004/01/28 12:02			0
2	BRS	L2	300	1 and(inspec\$4 or detec\$4)same (integrate\$1 near3 circuit\$1 or wafer\$1 or "IC"chip\$1 or printed near3 circuits)	USPAT	2004/01/28 12:04			0
3	BRS	L3	50	2 and(collimator or collima\$4) same(x-ray or x-rays or x-raying or x-rayed or x-ray\$3 near3 beam\$1 or gamma near3 ray\$1)	USPAT	2004/01/28 12:48			0
4	BRS	L4	15	3 and (multiaperture or multi-aperture or multi adj1 aperture or plurality near3 apertures or grid\$2 or mesh\$2)	USPAT	2004/01/28 12:51			0
5	BRS	L5	22	((collimator or collima\$4) with(x-ray or x-rays or x-raying or x-rayed or x-ray\$3 near3 beam\$1 or gamma near3 ray\$1)same semiconductor near3 wafer)	USPAT	2004/01/28 12:51			0
6	BRS	L6	0	5 same (multiaperture or multi-aperture or multi adj1 aperture or plurality near3 apertures or grid\$2 or mesh\$2)	USPAT	2004/01/28 12:51			0
7	BRS	L7	2	5 and (multiaperture or multi-aperture or multi adj1 aperture or plurality near3 apertures or grid\$2 or mesh\$2)	USPAT	2004/01/28 12:52			0
8	BRS	L17	1732	382/141-152.ccls.	USPAT	2004/01/28 13:25			0

	Type	L #	Hits	Search Text	Dbs	Time Stamp	Comments	Error Definition	Err ors
9	BRS	L18	162854	(sandwich\$4 or inbetween\$4 or in-between\$4 or between\$4 or therebetween\$4) near7 (array\$1 or aperture\$4 or grate\$1 or grating or diaphra\$4)	USPAT	2004/01/28 13:36			0
10	BRS	L19	169	17 and 18	USPAT	2004/01/28 13:31			0
11	BRS	L20	3891	18 near7 (semiconduc\$4 or wafer\$1 or IC or chip\$1 or integrated-circuit\$1)	USPAT	2004/01/28 13:36			0
12	BRS	L21	5	17 and 20	USPAT	2004/01/28 13:57			0
13	BRS	L22	381751	(sandwich\$4 or inbetween\$4 or in-between\$4 or between\$4 or therebetween\$4) same (array\$1 or aperture\$4 or grate\$1 or grating or diaphra\$4)	USPAT	2004/01/28 13:36			0
14	BRS	L23	30439	22 same (semiconduc\$4 or wafer\$1 or IC or chip\$1 or integrated-circuit\$1)	USPAT	2004/01/28 13:36			0
15	BRS	L24	86	17 and 23	USPAT	2004/01/28 13:37			0
16	BRS	L25	81	24 not 21	USPAT	2004/01/28 13:37			0